

<b>Notice of References Cited</b>	Application/Control No. 10/586,349	Applicant(s)/Patent Under Reexamination BARAK, AYALA	
	Examiner Nathan W. Schlientz	Art Unit 1616	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0054563	03-2006	Tsuneki et al.	210/697
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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